

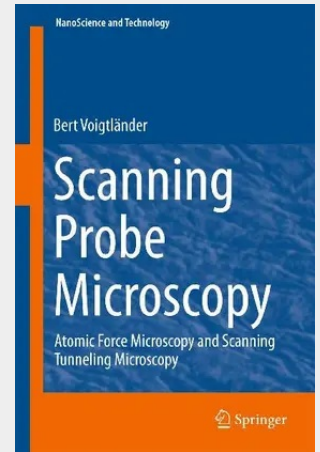
Voigtländer

Scanning Probe Microscopy

Atomic Force Microscopy and Scanning Tunneling Microscopy

This book explains the operating principles of atomic force microscopy and scanning tunneling microscopy. The aim of this book is to enable the reader to operate a scanning probe microscope successfully and understand the data obtained with the microscope. The chapters on the scanning probe techniques are complemented by the chapters on fundamentals and important technical aspects. This textbook is primarily aimed at graduate students from physics, materials science, chemistry, nanoscience and engineering, as well as researchers new to the field.

This book explains the operating principles of atomic force microscopy and scanning tunneling microscopy. The aim of this book is to enable the reader to operate a scanning probe microscope successfully and understand the data obtained with the microscope. The chapters on the scanning probe techniques are complemented by the chapters on fundamentals and important technical aspects. This textbook is primarily aimed at graduate students from physics, materials science, chemistry, nanoscience and engineering, as well as researchers new to the field.



213,99 €

199,99 € (zzgl. MwSt.)

Lieferfrist: bis zu 10 Tage

Artikelnummer: 9783662452394

Medium: Buch

ISBN: 978-3-662-45239-4

Verlag: Springer

Erscheinungstermin: 23.03.2015

Sprache(n): Englisch

Auflage: 2015

Serie: NanoScience and Technology

Produktform: Gebunden

Gewicht: 7214 g

Seiten: 382

Format (B x H): 160 x 241 mm

